

scf_ctrl.idl
high_cut high cut for central strip, set to 6 sigma
testTolerance set to 20%

sdm_calib_db.idl
id_strip
n_pedestal
n_sigma

sls_strip.idl spa_strip
id number 1->nok
id_strip full address (wafer+ladder etc)
id_cluster useless ?
adc_count in e- (in ADC count after scf)
noise_count empty after sls (filled after spa) useless here since scf picks noise in sdm_calib_par.idl
id_hits vect -> geant hits if one strip belongs to several hits
N_hits # of hits a strip belongs to
de redundant with adc_count
id_mchit key to montecarlo hit
id_mctrack -> used for the evaluation but redundant with id_hits

sls_ctrl.idl
NElectronInAMip in e-
ADCdynamics in MIPS
A128Dynamics in MIPS
NBitEncoding number of ADC bit for encoding
NStripInA Cluster
PairCreationEnergy in GeV
ParDiffP
ParDiffN
ParIndRightP
ParIndRightN
ParIndLeftP
ParIndLeftN
DAQCutValue set to 3 sigma

sdm_geom_par.idl
N_layer SSD layer number
N_ladder Nbr of ladders per layer
N_waf_per_ladder Nbr of wafers per ladder
N_alice_per_side Nbr of alice128C per wafer side
N_strip_per_side Nbr of strips per wafer side
L_strip_pitch strip pitch
L_stereo_angle half stereo angle
L_wafer_tot_l half wafer total length
L_wafer_tot_w half wafer total width
L_wafer_tot_t half wafer total thickness
L_wafer_act_l half wafer active length
L_wafer_act_w half wafer active width

scf

